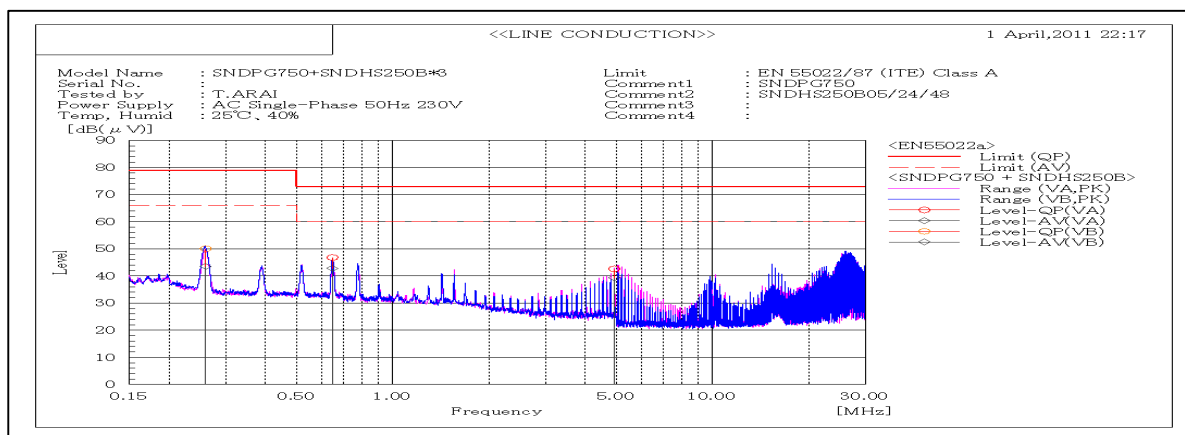
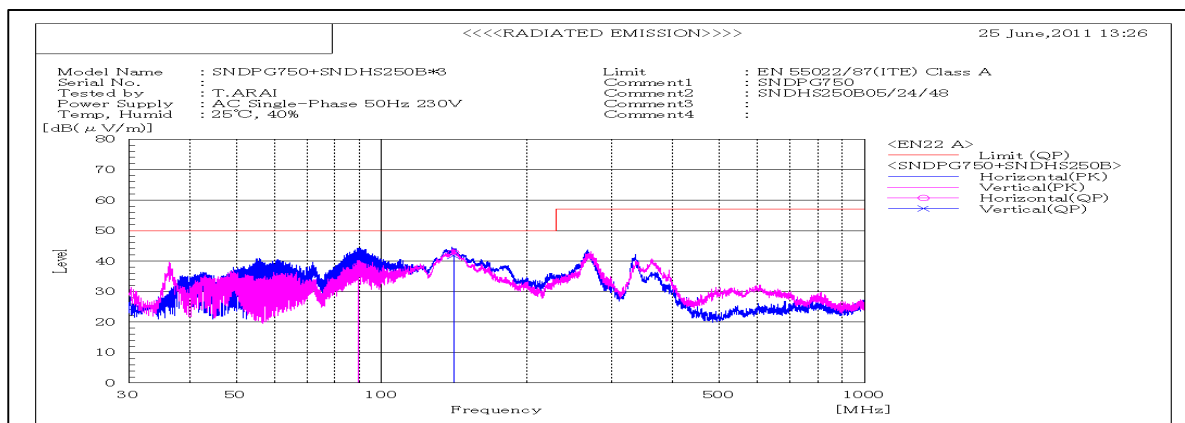


DATA SHEET		Date	20-Jul-11
Model	SNDPG750+SNDHS250Bx3(5/24/48V)	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.ARAI



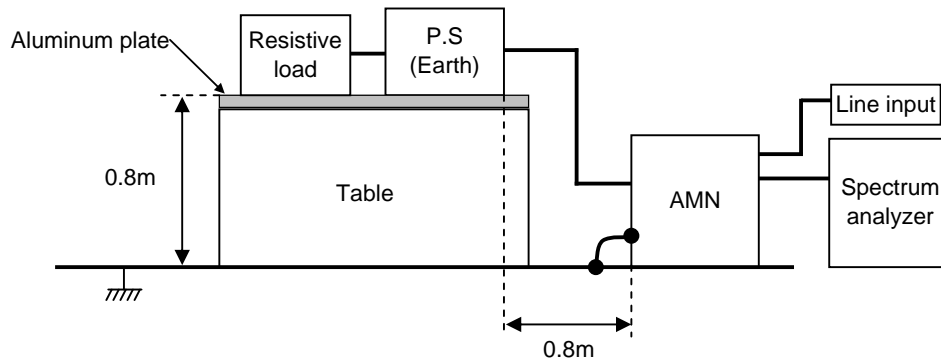
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.260		VB	40	33.4	10.1	50.1	43.5	79	66	28.9	22.5	Pass	
0.647		VA	36.7	32.7	10.1	46.8	42.8	73	60	26.2	17.2	Pass	
4.928		VA	32.1	28.8	10.5	42.6	39.3	73	60	30.4	20.7	Pass	



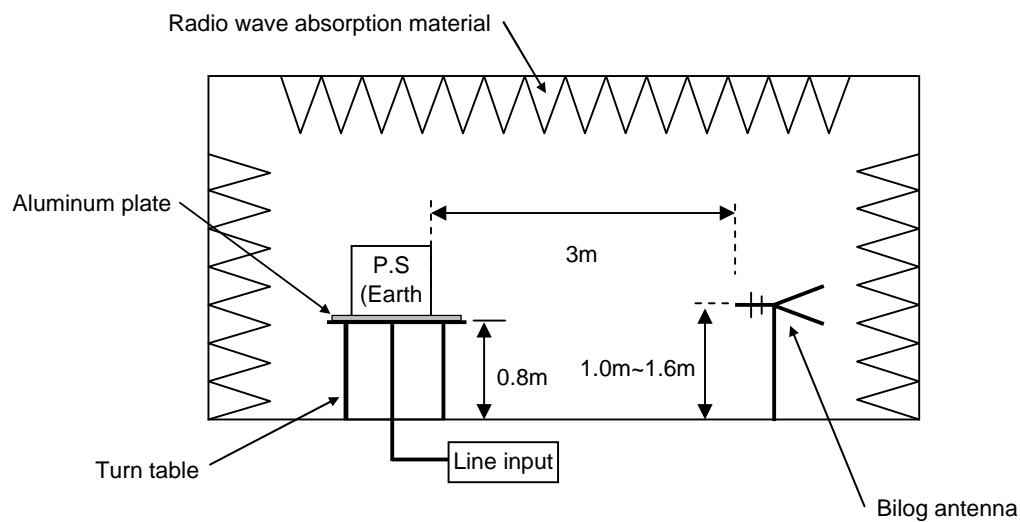
Frequency MHz	Polariz ation	Level Check	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				QP		QP	QP	QP				
89.334	H		Stable	61.5	-23.1	38.4	50	11.6	Pass	127	30	
140.894	H		Stable	62.8	-20	42.8	50	7.2	Pass	156	250	
140.965	V		Stable	61.8	-20	41.8	50	8.2	Pass	157	163	

DATA SHEET		Date	20-Jul-11
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.ARAI

1. Line conduction



2. Radiated emission



Test: EMI

Model Name: SNDPG750+SNDHS250B05+SNDHS250B24+SNDHS250B48

○ Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○ Test Circuit

